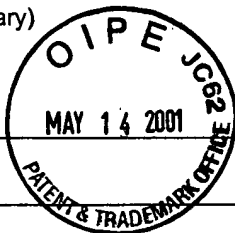


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U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

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1.							

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

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1.	<i>Jc</i>	Anil K. Jain, "Fundamentals Of Digital Image Processing," Prentice Hall Information And System Sciences Series, Thomas Kailath, Series Editor, Pages 357-358 and 409-410

Examiner:

Jon Chang

Date Considered:

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Examiner:

John Chang

Date Considered:

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